$$\frac{O1.}{P_1(t+\Delta t)} = P_1(t) - \lambda_1 \Delta t P_1(t)$$

$$P_2(t+\Delta t) = P_2(t) + \lambda_1 \Delta t P_1(t)$$

$$-\lambda_2 \Delta t P_2(t)$$

$$P_{3}(t+\Delta t) = P_{3}(t) + \lambda_{2}\Delta t P_{2}(t)$$

$$\frac{dP_{1}(t)}{dt} = -\lambda_{1}P_{1}(t)$$

$$\frac{dP_2(t)}{dt} = \lambda_1 P_1(t) - \lambda_2 P_2(t)$$

$$\frac{dP_3(t)}{dt} = \lambda_2 P_2(t)$$

$$\frac{dP_2(t)}{dt} + \lambda_2 P_2(t) = \lambda_1 e^{-\lambda_1 t}, v(x) = \int \lambda_2 dt = \lambda_2 t + C$$

$$P_2(t) = e^{-\lambda_2 t} \int e^{-\lambda_2 t} \lambda_1 e^{-\lambda_1 t} dt$$

$$= ce^{-\lambda_2 t} - \frac{\lambda_1}{\lambda_1 + \lambda_2} e^{-(\lambda_1 + \lambda_2) t}$$

$$c = \frac{\lambda_1 + \lambda_2}{\lambda_1 + \lambda_2}$$

$$P_{2}(f) = \frac{\lambda_{1}}{\lambda_{1} + \lambda_{2}} \left[e^{-\lambda_{2} t} - e^{-(\lambda_{1} + \lambda_{2}) t} \right]$$

$$P_{3}(t)=1-P_{1}(t)-P_{2}(t)$$

$$=1-e^{-\lambda_{1}t}-\frac{\lambda_{1}}{\lambda_{1}+\lambda_{2}}\left[e^{-\lambda_{2}t}-e^{-(\lambda_{1}+\lambda_{2})t}\right]$$

$$R_{p}(t) = P_{1}(t) + P_{2}(t)$$

$$= e^{-\lambda_{1}t} + \frac{\lambda_{1}}{\lambda_{1}+\lambda_{2}} \left[e^{-\lambda_{2}t} - e^{-(\lambda_{1}+\lambda_{2})t} \right]$$

MTTF =
$$\frac{1}{\lambda} + \frac{1}{\lambda_2}$$

Q2.
$$D(t) = \beta_1 t$$
 $\beta_1 \sim LogNorm(\mu_1, \sigma_1^2)$

Failure: $D(t) > Df & D_f \sim LogNorm(\mu_2, \sigma_2^2)$
 $P(\beta_1 t > D_f) = F_T(t)$
 $\beta_1 = e^{\mu_1 + \sigma_1 Z}$
 $\beta_1 = e^{\mu_2 + \sigma_2 Z}$
 $\beta_1 = e^{\mu_1 + \sigma_1 Z}$
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 $\beta_1 = e^{\mu_1 + \sigma_1 Z}$
 $\beta_1 = e^{\mu_2 + \sigma_2 Z}$
 $\beta_1 = e^{\mu_2 + \sigma_2$

Q3. Jet engine 5 modules

23A B C D E

once daily, average 5 hours

· From among the exponential, Weibull, normal, and lognormal distributions, find a best-fit failure distribution.

From histogram & best fit line plots, the best fit failure distributions:

23A: Weibull (B= 2.51787, 0=1332.4332)

23B: Exponential (7= 1/347.987)

230: Weibil (B= 2.089338, A= 500.781)

230: Exponential (7 1/1798.82)

23E: Weibull (B=1.16203, 0= 2836.11)

Repair time: Weibull (B= 1.24/27, B= 17.0590)

· Compute performance measurements

First, calculate system hazard rate, 2(t)

$$\lambda(t) = \lambda_B + \lambda_D + \sum_{i \in \{A,C,E,R\}} \frac{\beta_i}{\theta_i} \left(\frac{t}{\theta_i}\right)^{B-1}$$

$$R(t) = e^{-\int \lambda(t) dt}$$

$$= e^{-\int \lambda(t) dt} + \sum_{i \in \{A,C,E,R\}} \left(\frac{t}{\theta_i}\right)^{\beta_i}$$

Now, we can plug the values into this formula in futhon to calculate the measurements:

o 90th percentile of the repour time = tao

- · Which subsystem displays the worst reliability?

 Clearly, the 23B module has the worst reliability out of all the modules, based on the MTTF and the distribution/ histogram of failure times.
- · What should the reliability of that subsystem be to achieve a system reliability of R(10 missions) = 0.9?

Current R(10 missions) = 0.827774

Need to solve for his in the equation below:

$$0.9 = e^{-\left[\lambda_{\text{B}}^* t + \lambda_{\text{D}} t + \sum_{i \in \{A,C,E,R\}} \left(\frac{t}{\theta_i}\right)^{\beta_i}\right]}$$

Use the Python solver, we get a $\lambda_B^* = \frac{1}{832.92989}$ Reliability of 23B = $R_B(t) = e^{-\frac{t}{832.92989}}$

RB(10 missions) = 0.941737

Q4. a. Using TTF info (only): Solve using MLE on poll of 15 i'd Weibull r.v.s ∠(β,θ)= / δ(t;) / R(120000) where $F = \{1, 2, 3, 5, 6, 7, 8, 9, 103\}$ (specimens with complete $C = \{4, 11, 12, 13, 14, 153\}$ (specimens of censored failure data) B(ti) = = = (ti) = -(ti) = 0, 870, 870, R(120 000) = 1- F(120 000) = e (120 000/8) B In[2(B, 8)] = 6 In[1-F(120000)] + > In b(ti) Using MLE solver on R: 0=166420.226 B= 1.07888043 - (+) B F(t) = (- R(t), R(t) = e let F(t) = 0 e-(4/8) P = 1-0 (+/0) = -In(1-d) B(Int - In0) = In (-In (1-0)) In(-In(1-a)) + In 0

b. Assume that the degradation signals follow a linear degradation path: DB= B1+B2t

$$B_1 \sim MB_1$$
, $\beta_2 \sim N(MB_2, \sigma_{B_2}^2)$
 $D_1 \sim N(MB_1 + MB_1, \sigma_{B_2}^2 + \sigma_{B_2}^2)$
 $F_T(t) = P(\beta_1 + \beta_2 t > D_1)$

$$P(B_2 \leq X) = \Phi\left[\frac{X - MB_2}{\sigma_{B_2}}\right]$$

$$F_T(t) = P\left\{T \leq t\right\} \approx \Phi\left[\frac{t - \frac{D_8 - MB_1}{MB_2}}{\frac{\sigma_{B_2} t}{MB_2}}\right]$$

From numerical estimation using the data, BIN MBI= 8.39793572

B2~ N(5.2731428×105, (8.9685798×10-6)2)

C. Assume the same linear degradation path, use approximate degradation path to estimate pseudo failure times.

Pseudo random failure times = 108266.44, ..., 146556.57

After estimating the 15 pseudo random failure times, the estimated weiboll distribution has povamerers.

d. Bootstrapping:

From numerical estimation of the 15 paths

$$\beta_{1} \sim \mu_{\beta_{1}} = 8.39793572$$

 $\beta_{2} \sim N(5.2731428 \times 10^{5}, (8.9685798 \times 10^{-6})^{2})$ $\hat{\theta}_{\beta}$

$$F_{\tau}(t) = p \{ T \leq t \} \approx \Phi \left[\frac{t - \frac{D_{\delta} - \mu_{\beta_1}}{\mu_{\beta_2}}}{\frac{\sigma_{\beta_2} t}{\mu_{\beta_2}}} \right]$$

Si = D(ti; B_1 , B_2) + E_{ij} , where for each i, there will be 35 equally spaced tij points from 0 to 120 000, and E_{ij} $N(0, 0.63382^2)$ which is the standard dev. of the residual data points.

After running algorithm to calculate Bootstrap (onfidence Intervals at B=50,000 & $\alpha=0.1$, the confidence intervals are as follows:

 $\hat{F}(102795.66) = 0.1$ $\left[F(102795), F(102795)\right] = \left[7.7561 \times 10^{-5}, 0.27012\right]$

 $\hat{F}(112316.98) = 0.25$ $[F(112316), \hat{F}(112316)] = [0.016758, 0.49062]$

 $\hat{F}(125201.70) = 0.5$ [F(125201), F(125201)] = [0.14228, 0.85985]

Ê(141425.69) = 0.75

[F(141425), F(141423)] = [0.49426, 0.98548]

£ (160097.66) = 0.9

[F(160097), F(160097)] = [0.86178, 0.99901]